



Computational Electromagnetics
Laboratory



Report from TU-Darmstadt

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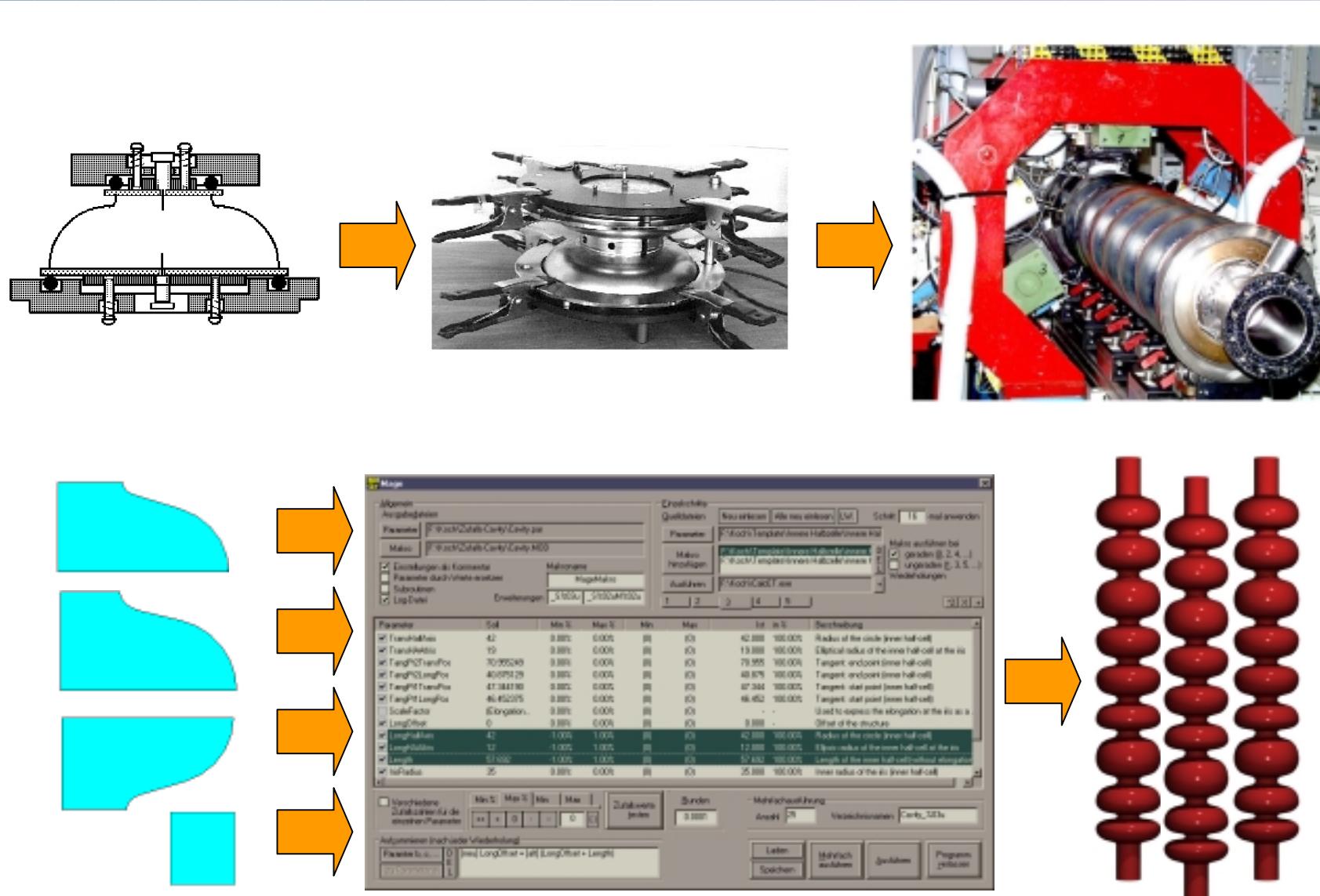


Reports from TU-Darmstadt

- *Computational Electromagnetics Laboratory*
 - ◆ Results from W. Mueller
 - ◆ Detailed Numerical Study of Space Charge Effects in the FEL rf-gun (PITZ)
 - ◆ V-Code Alignment Utility
 - ◆ A Code for Longitudinal Wake Field Calculation
 - ◆ Investigation of Surface Roughness Wake Fields

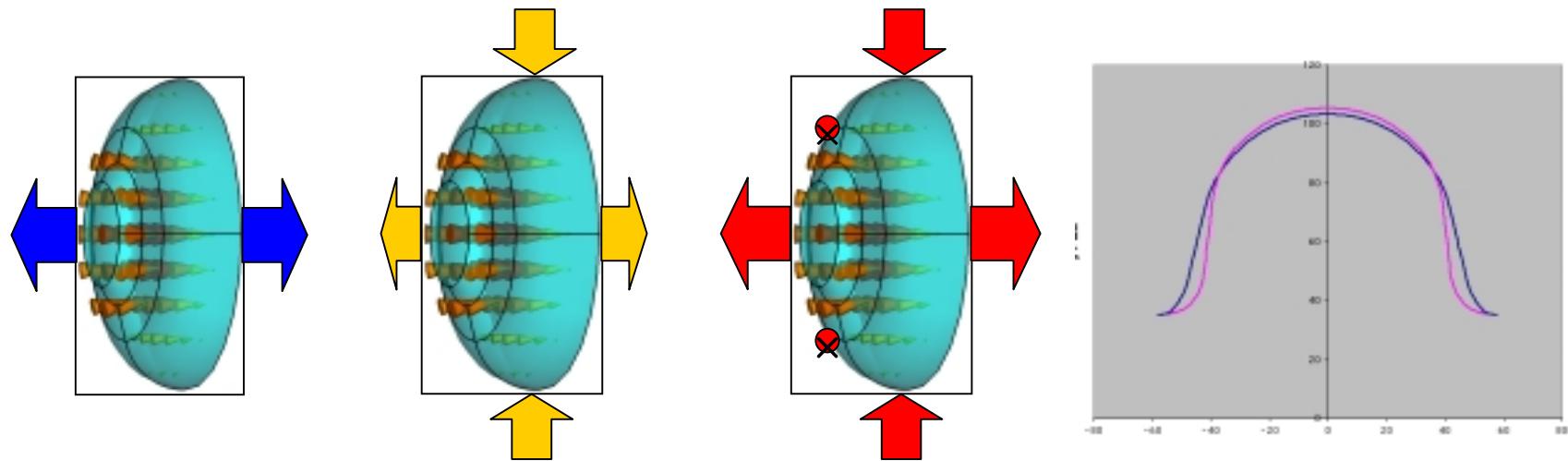


Simulation of Production Procedure



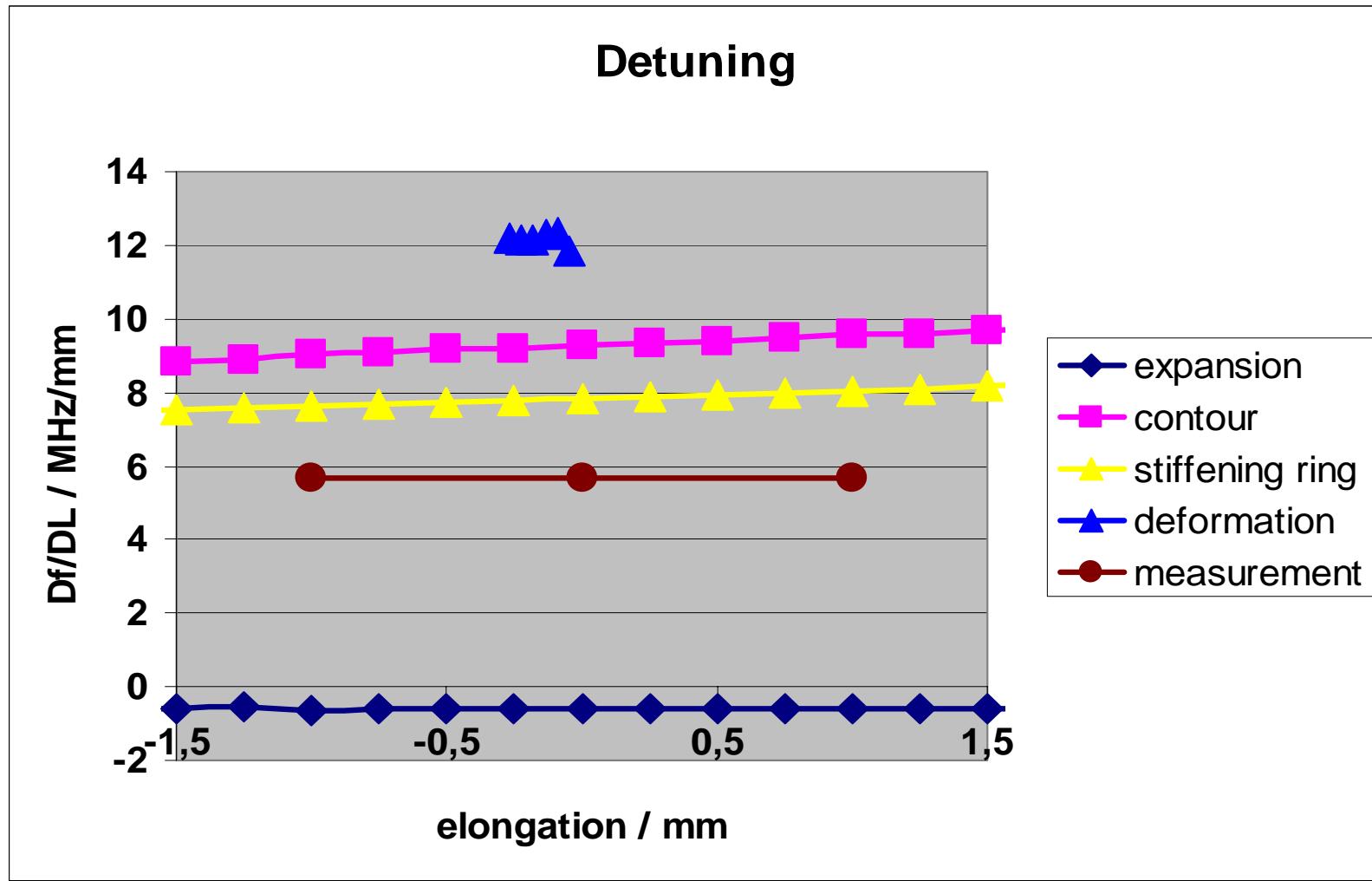
Different Methods of Deformation

- Linear Expansion
- Constant Length of 2D-Contours
- Constant Contours with Stiffening Ring
- Deformation from Numerical Simulation



Results

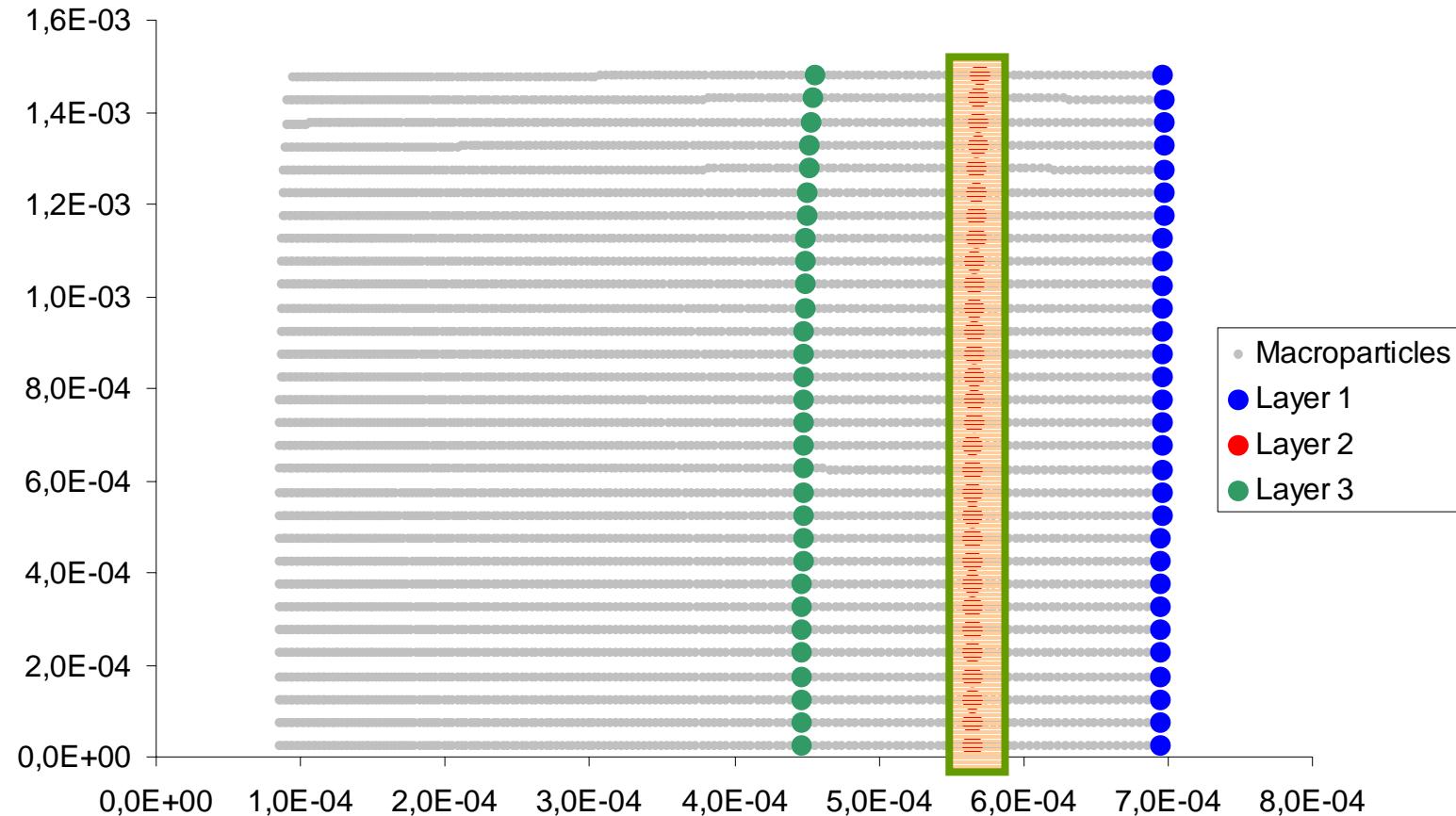
- Detuning of a Half Cell in MHz/mm:





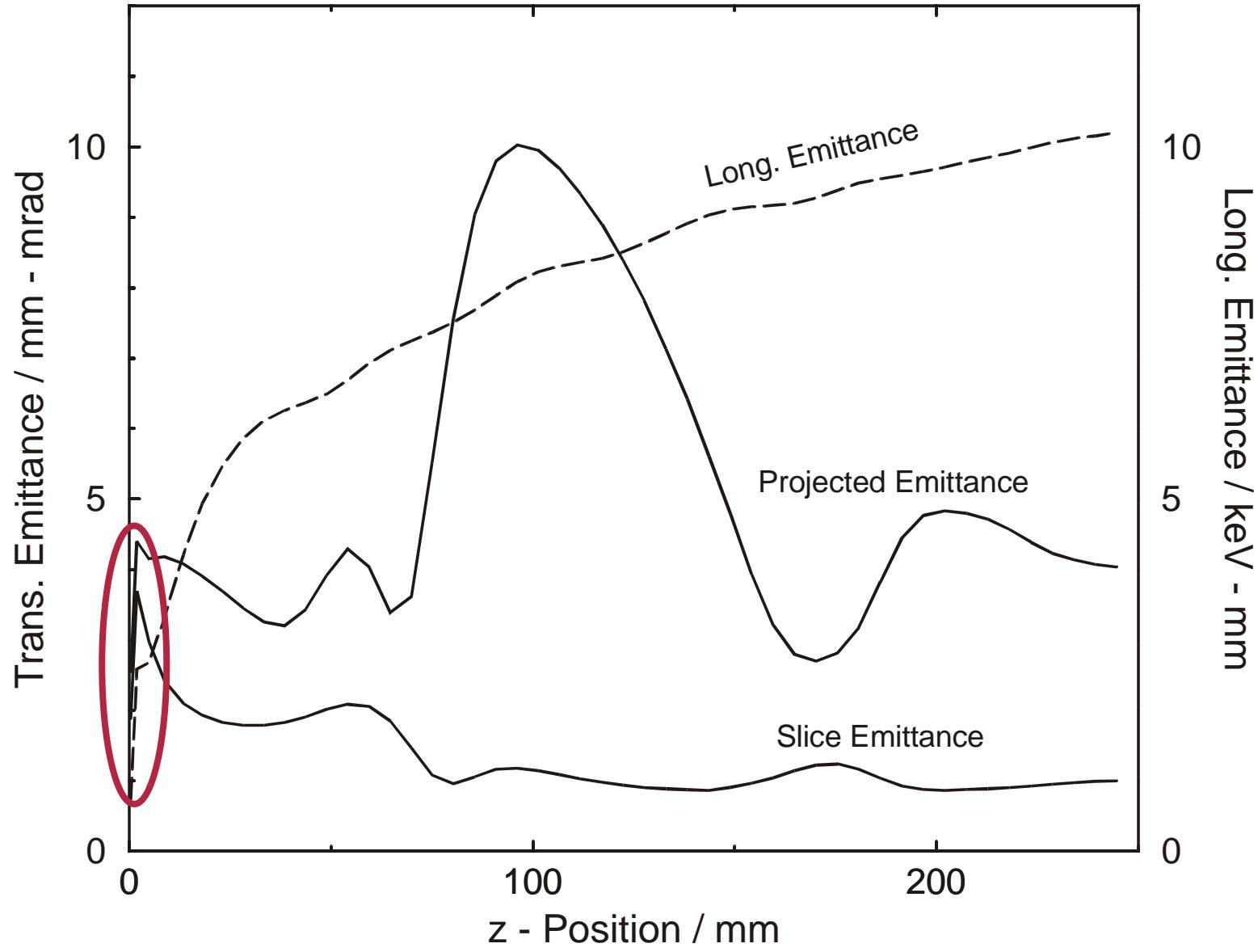
Space Charge Effects in the RF-Gun: Emittance Formation Study

Beam slices



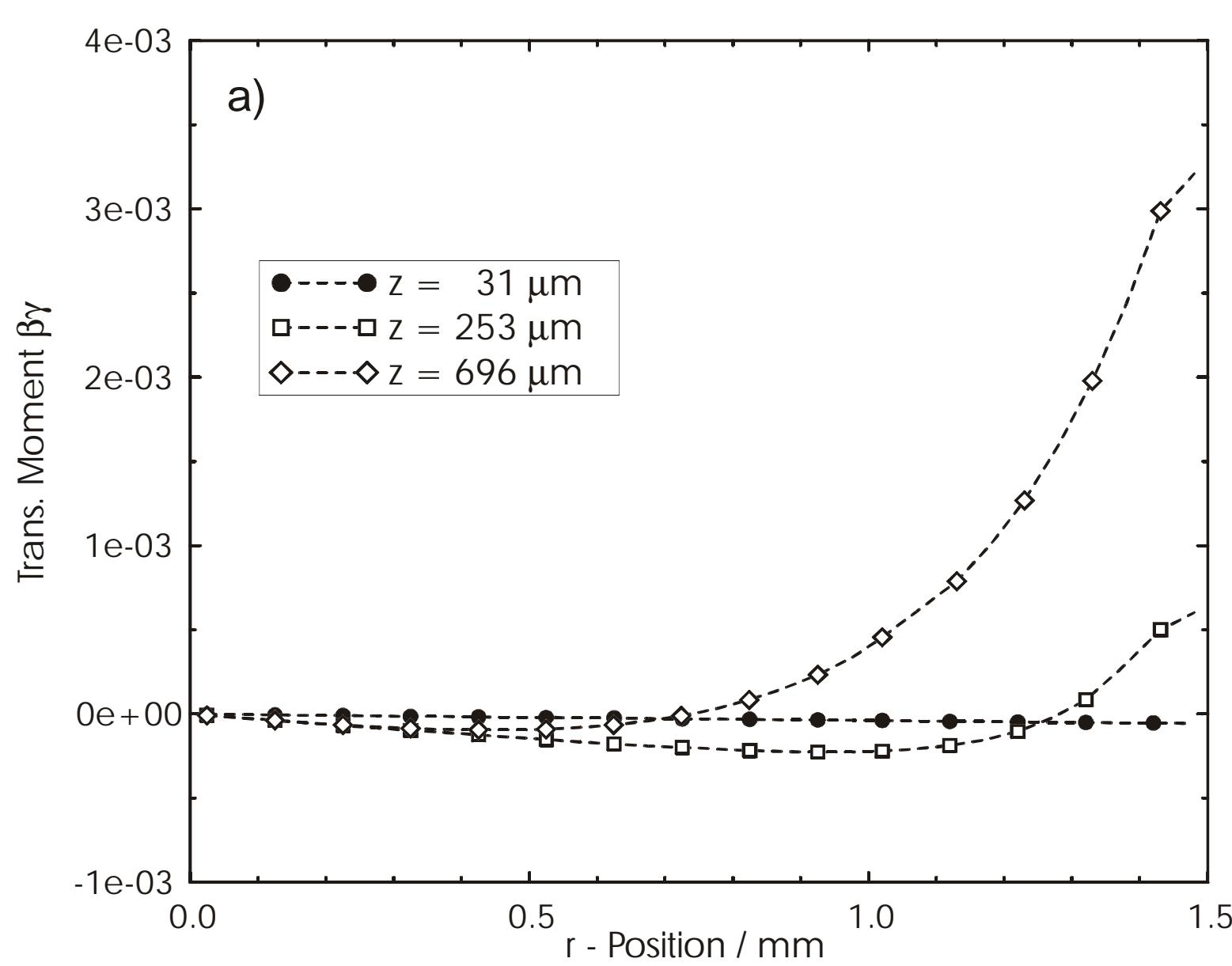


Space Charge Effects in the RF-Gun: Emittance Formation Study



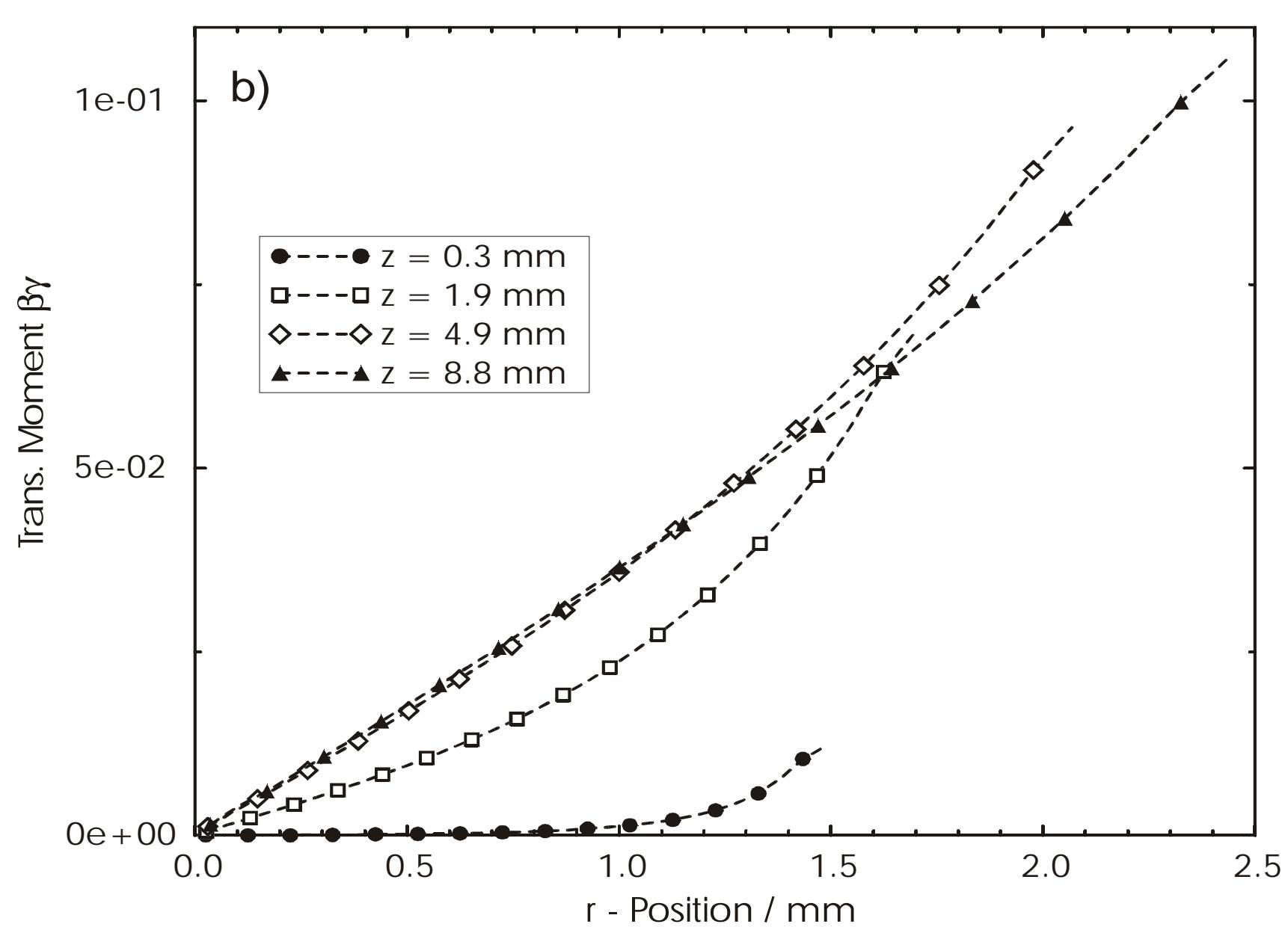


Space Charge Effects in the RF-Gun: Emittance Formation Study



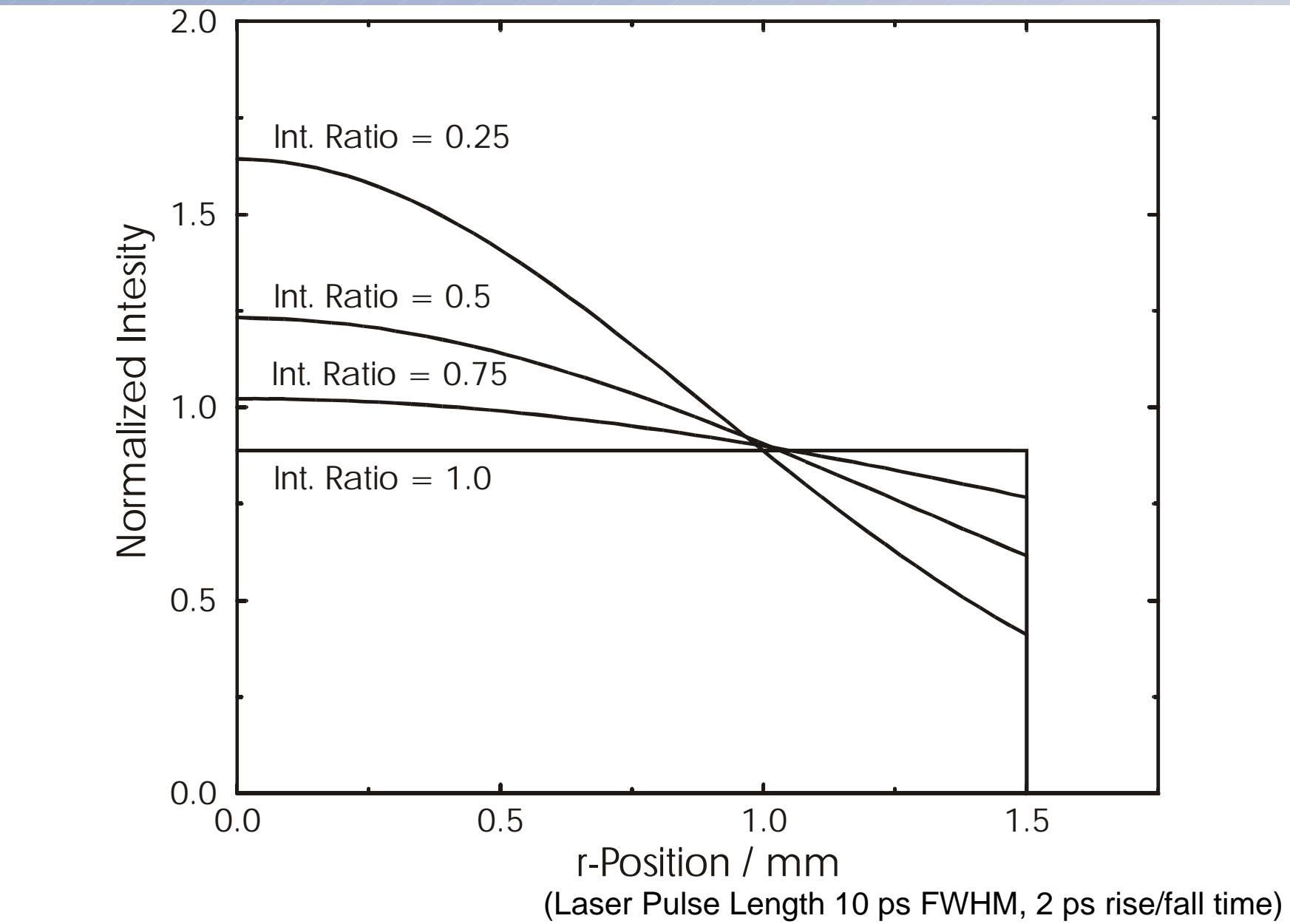


Space Charge Effects in the RF-Gun: Emittance Formation Study



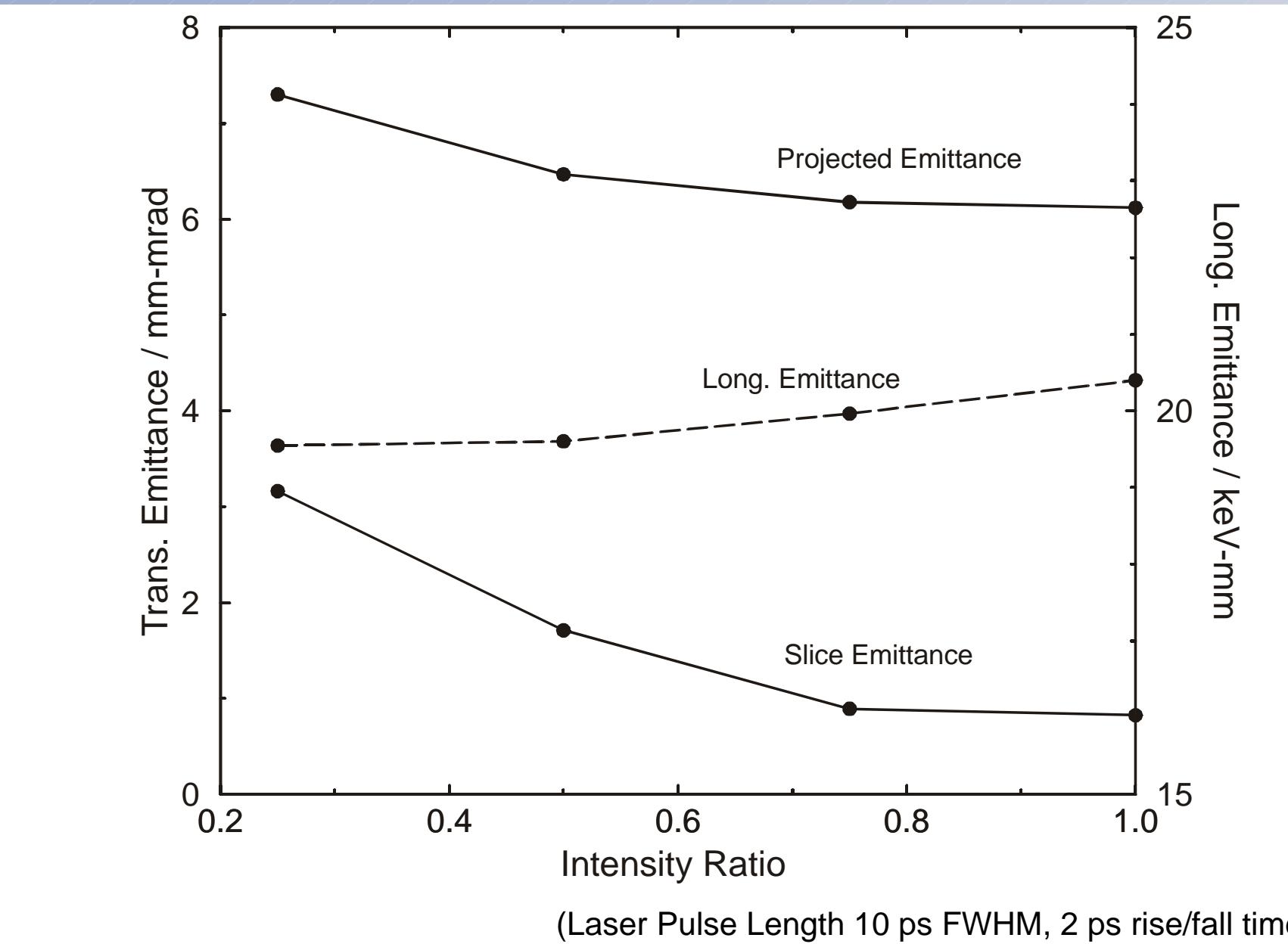


Influence of Transverse Laser Profiles on Beam Emittance at Gun Exit



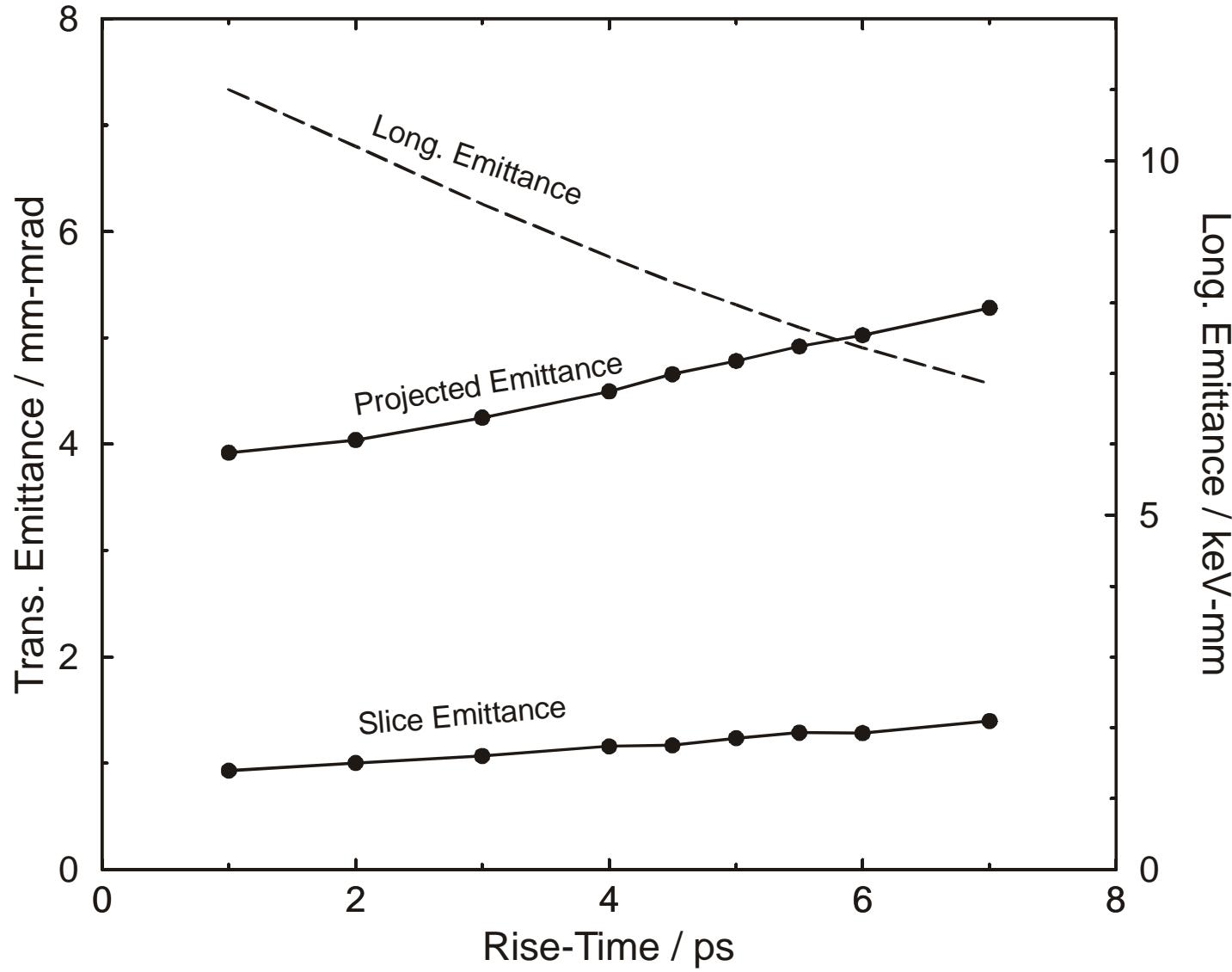


Influence of Transverse Laser Profiles on Beam Emittance at Gun Exit



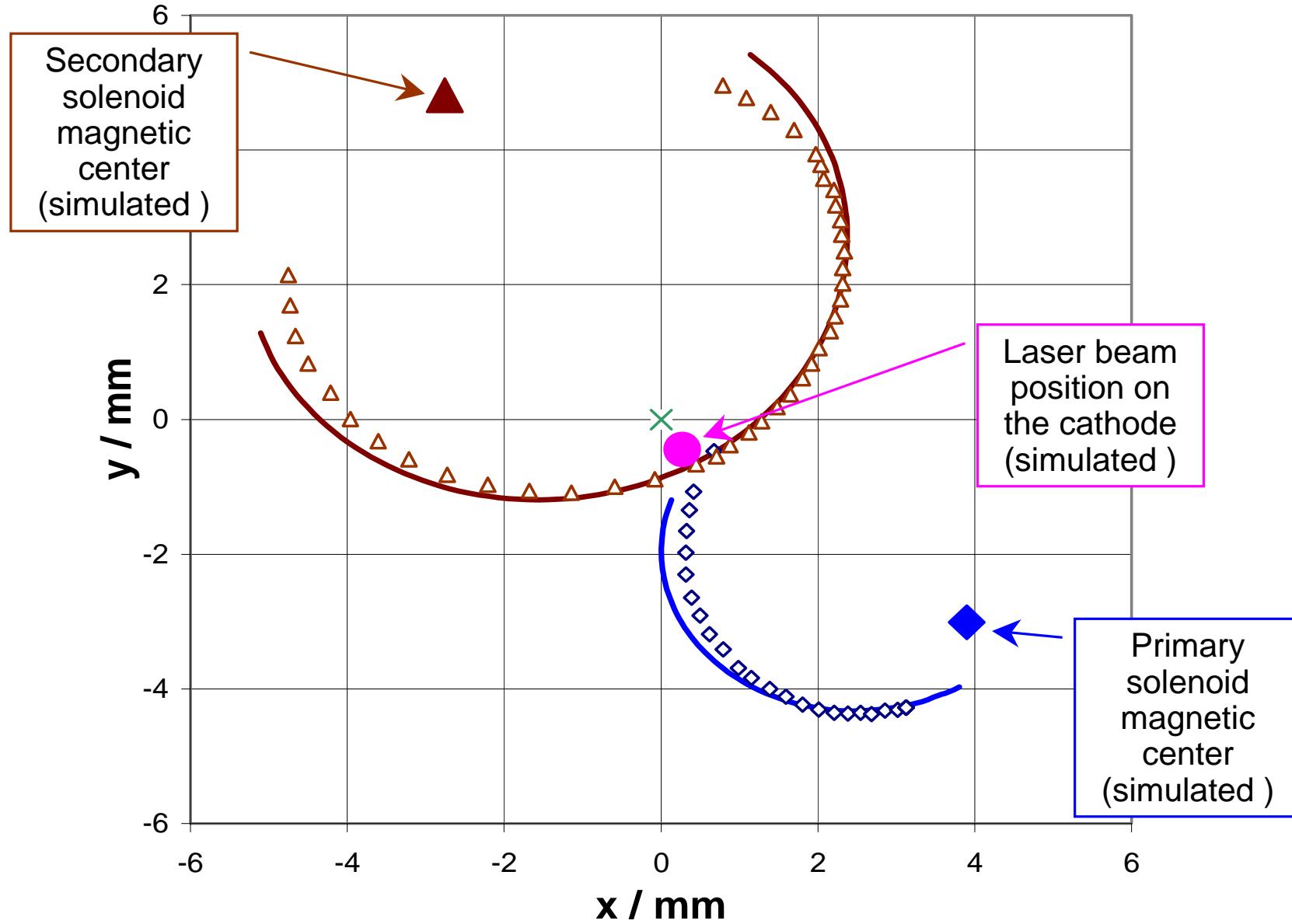


Dependency of the Emittances at the Gun Exit On the Laser Rise Time



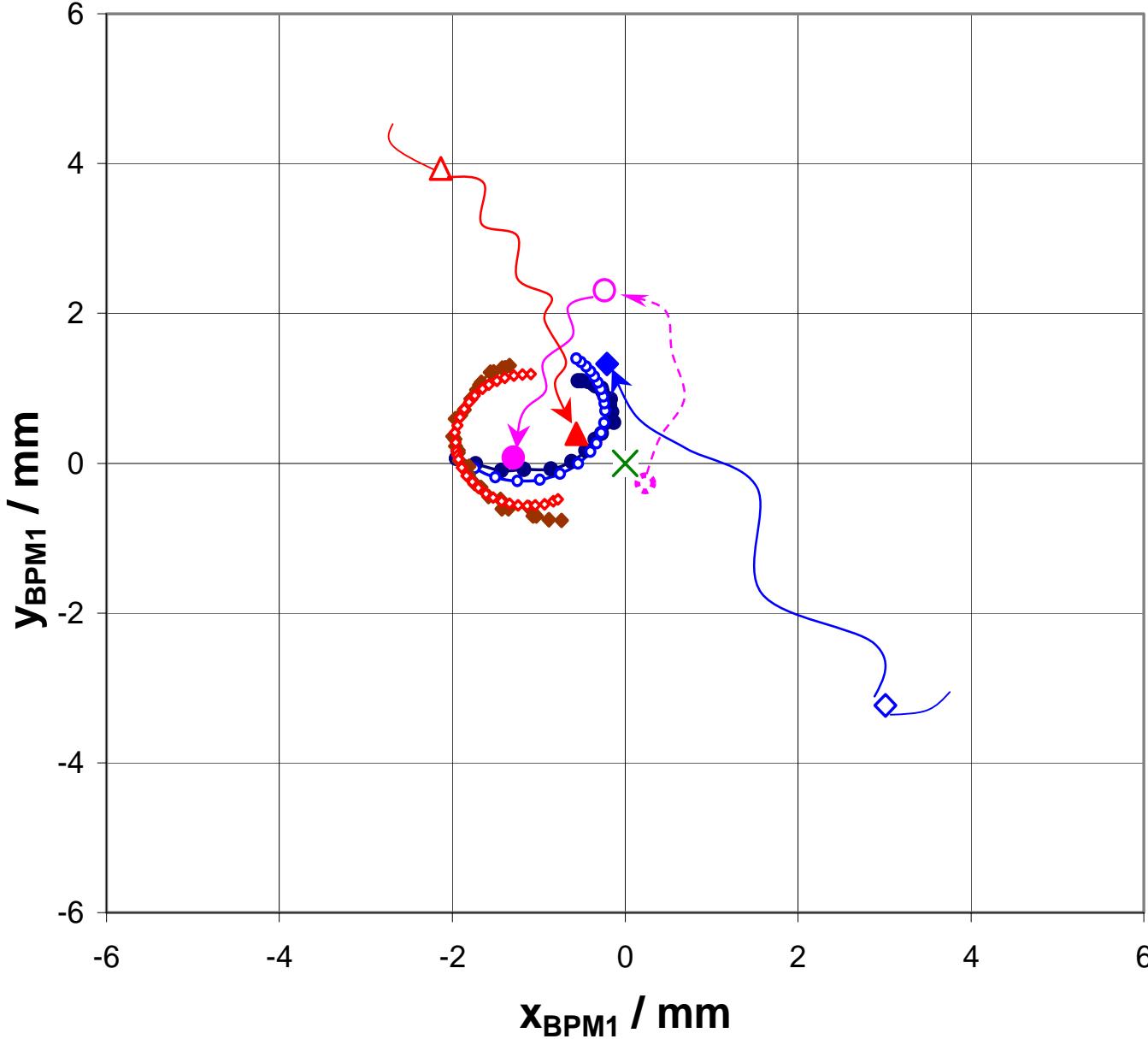


TTF Gun Alignment Study: Measurements & Simulations



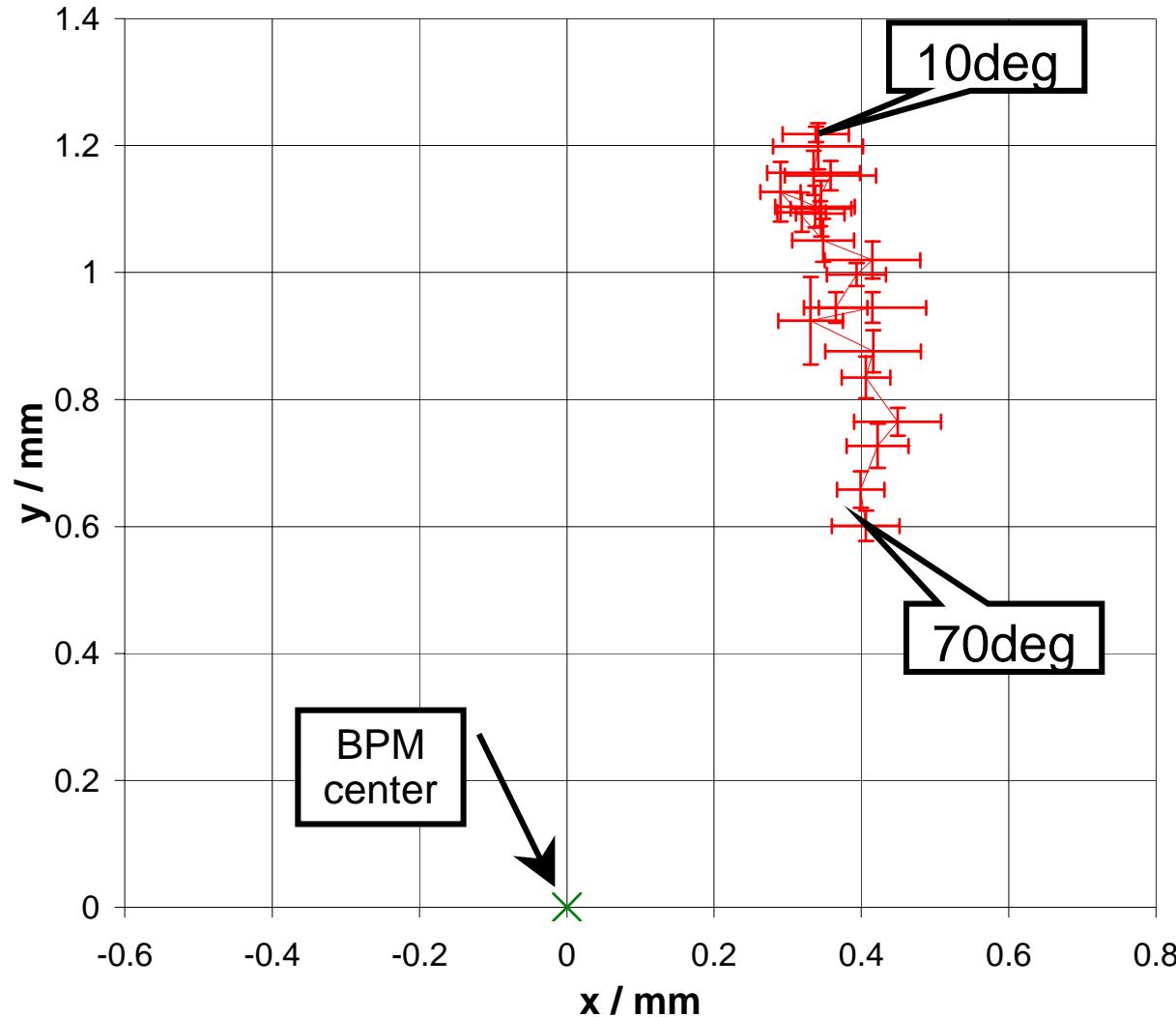


TTF RF-Gun Alignment: First Steps





BPM1 Readings vs RF-Phase (with both solenoids off)

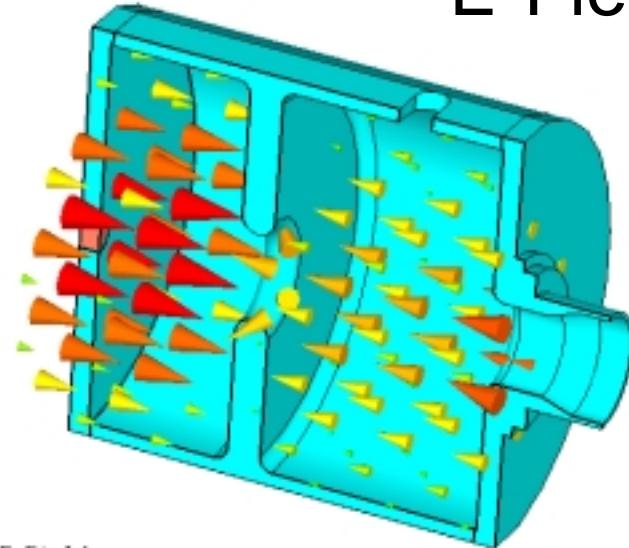


RF mode offset is to be taken into account



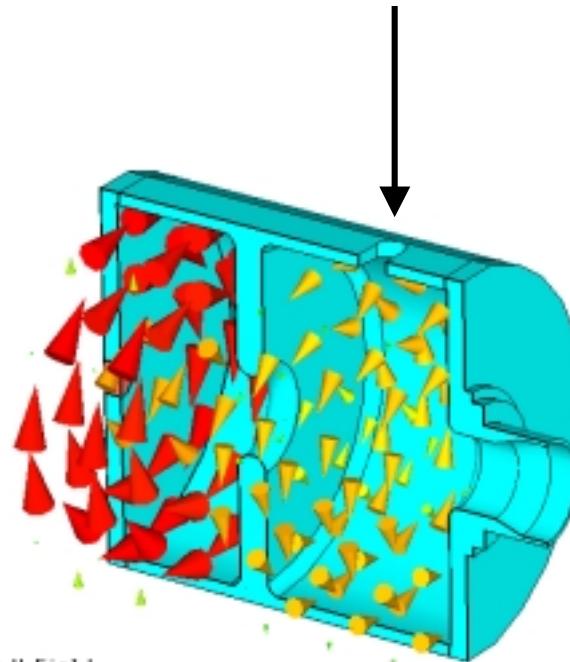
π -mode Offset Study

E-Field



Type = E-Field
Monitor = Mode 2
Maximum = $2.82164e+007$ V/m
Max. Arrow = $1.82635e+007$ V/m
Frequency = 1.38765
Phase = 0 degrees

H-Field

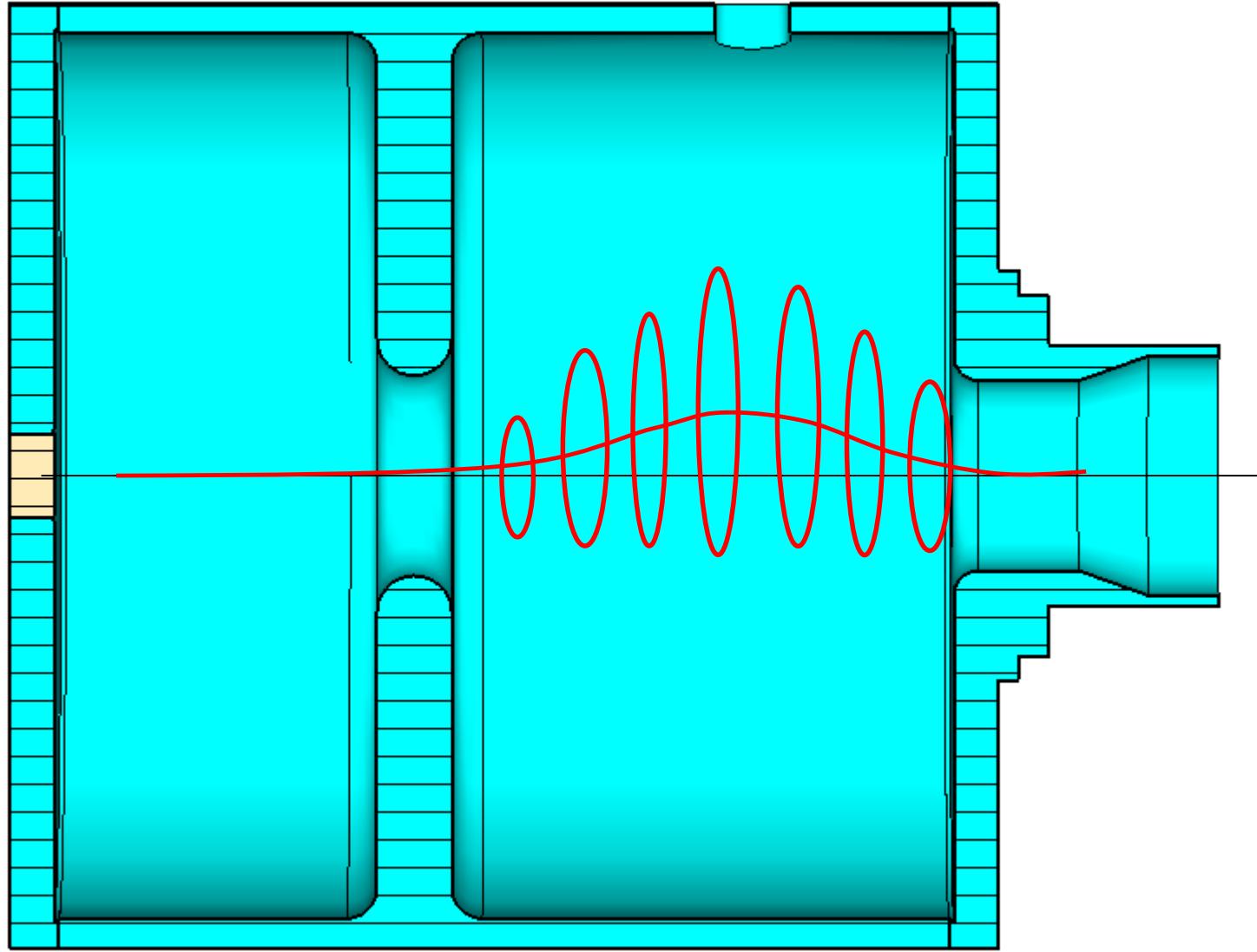


Type = H-Field
Monitor = Mode 2
Maximum = 51082.8 A/m
Max. Arrow = 31529.9 A/m
Frequency = 1.38765
Phase = 98 degrees

0 $3.15e+004$ A/m

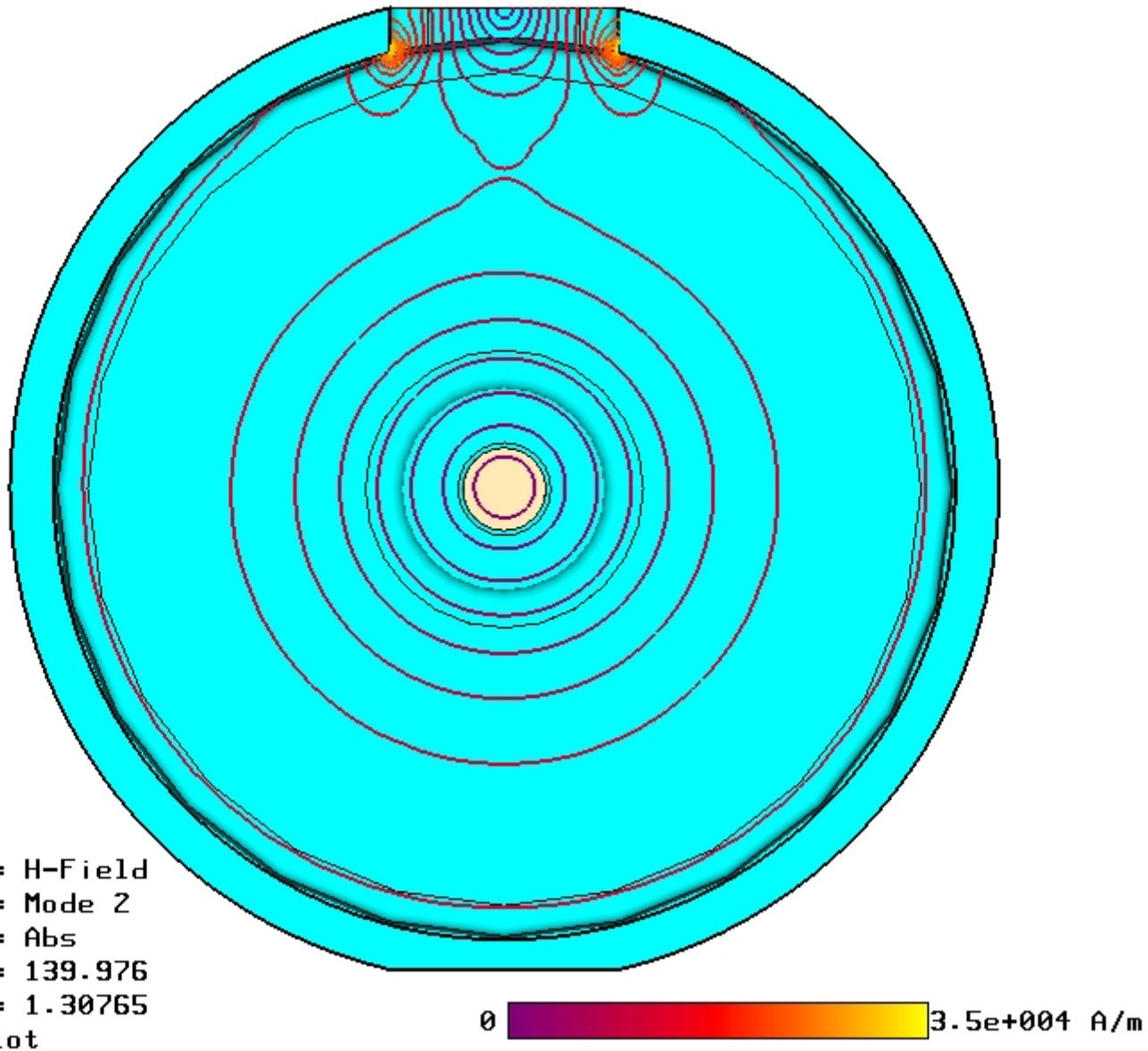


π -mode Offset Study



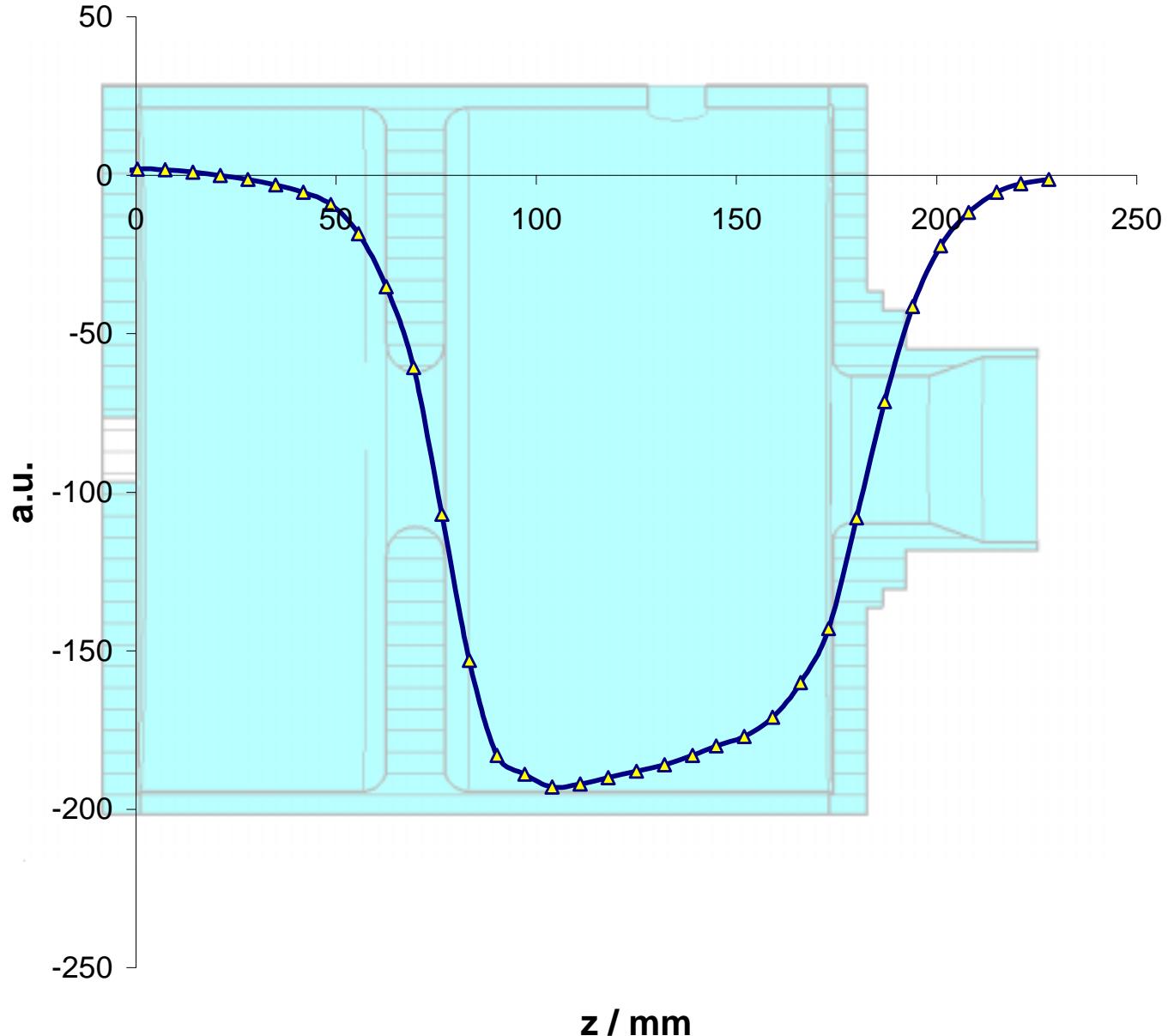


π -mode Offset Study : Magnetic Field Isolines



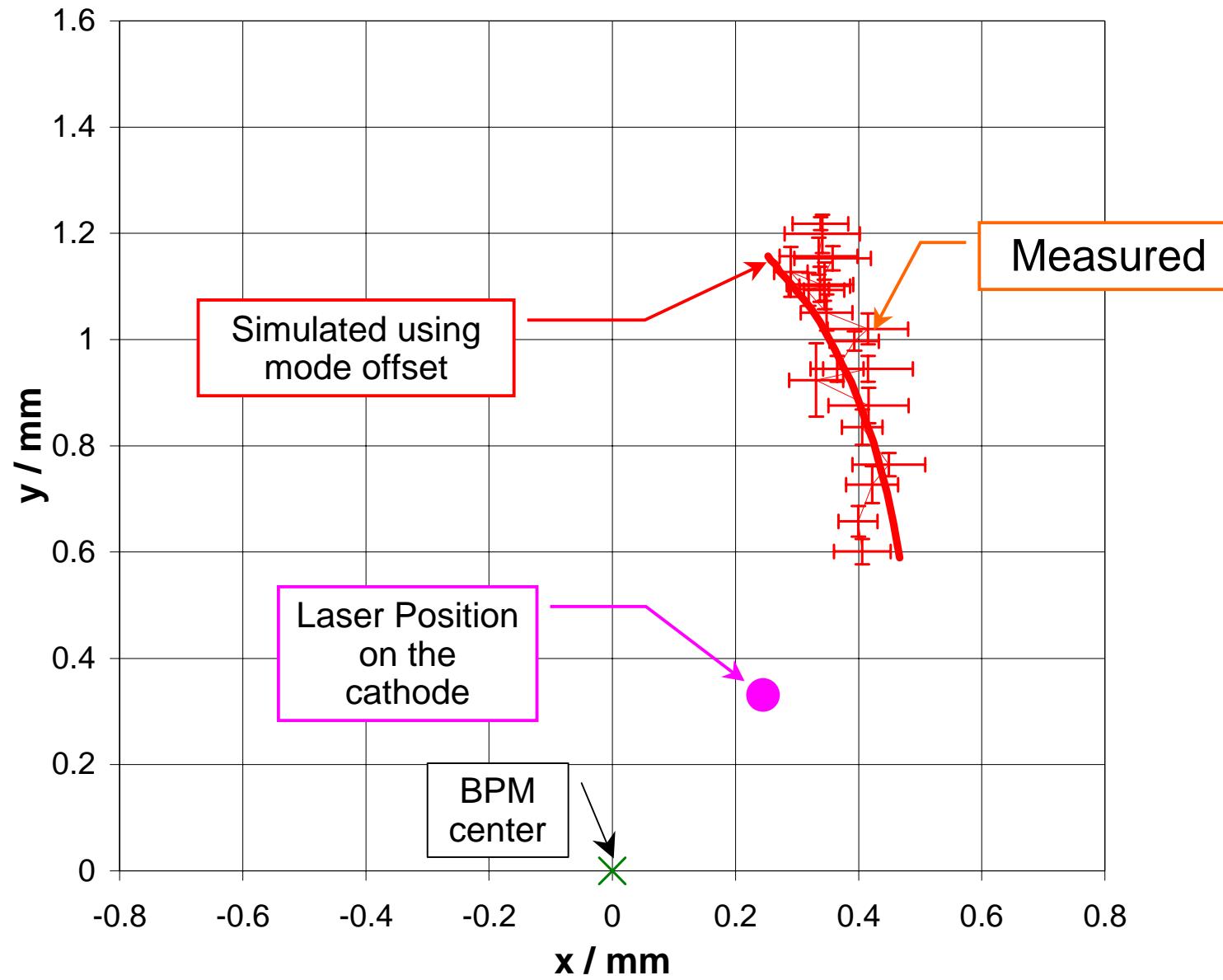


π -mode Offset Study: H_x on the cavity axis



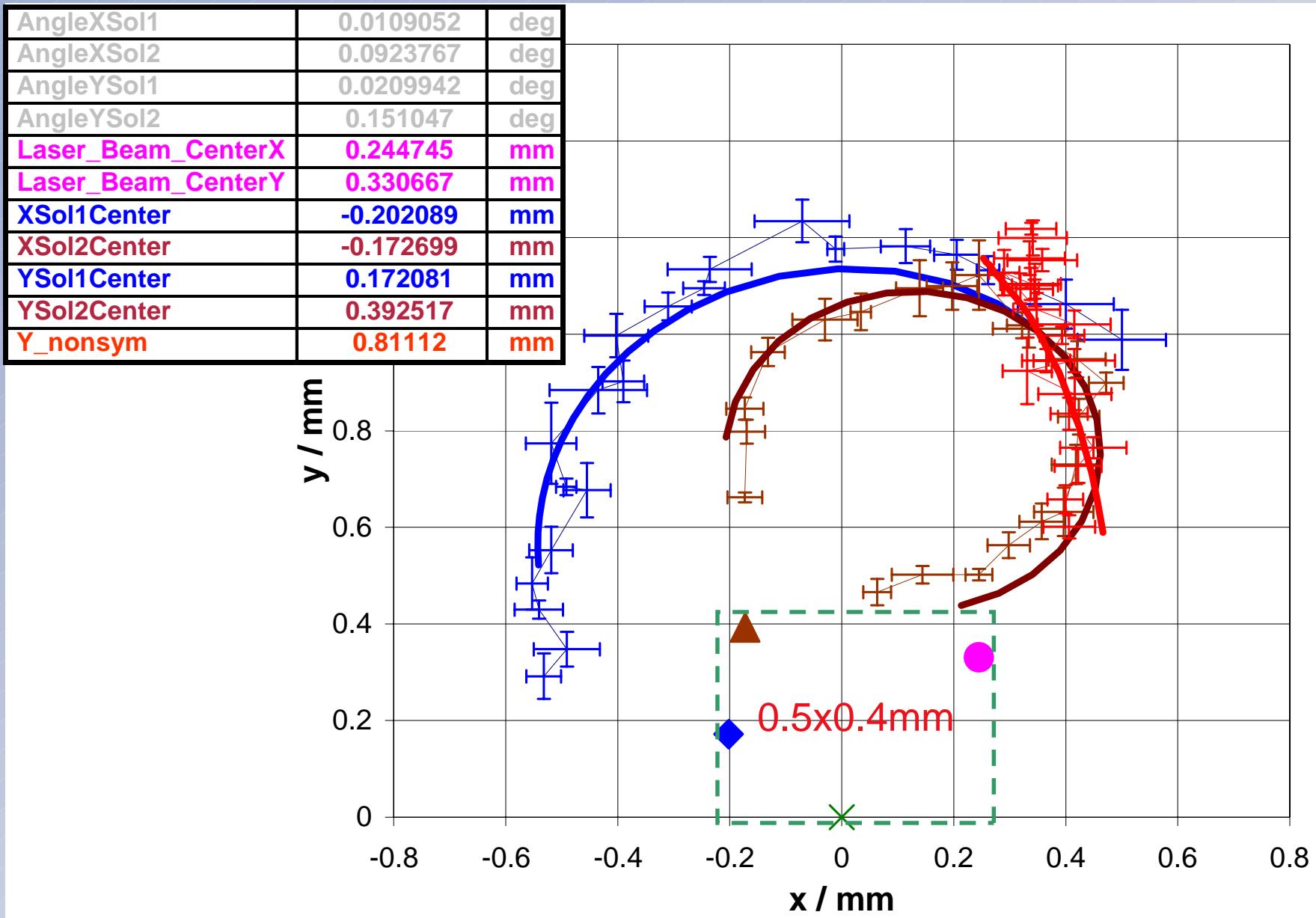


BPM1 Reading vs RF-Phase



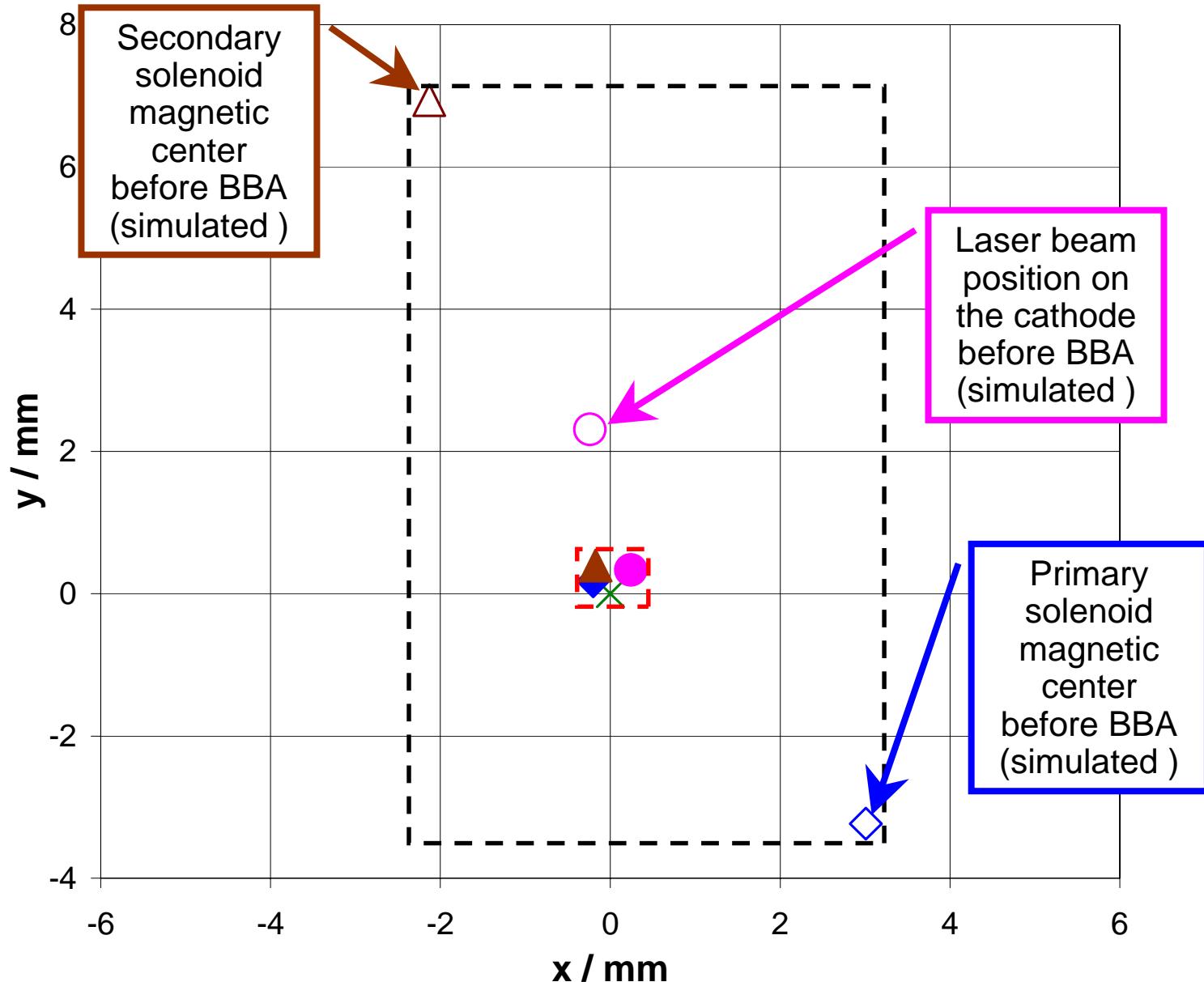


Final Measurements&Simulations



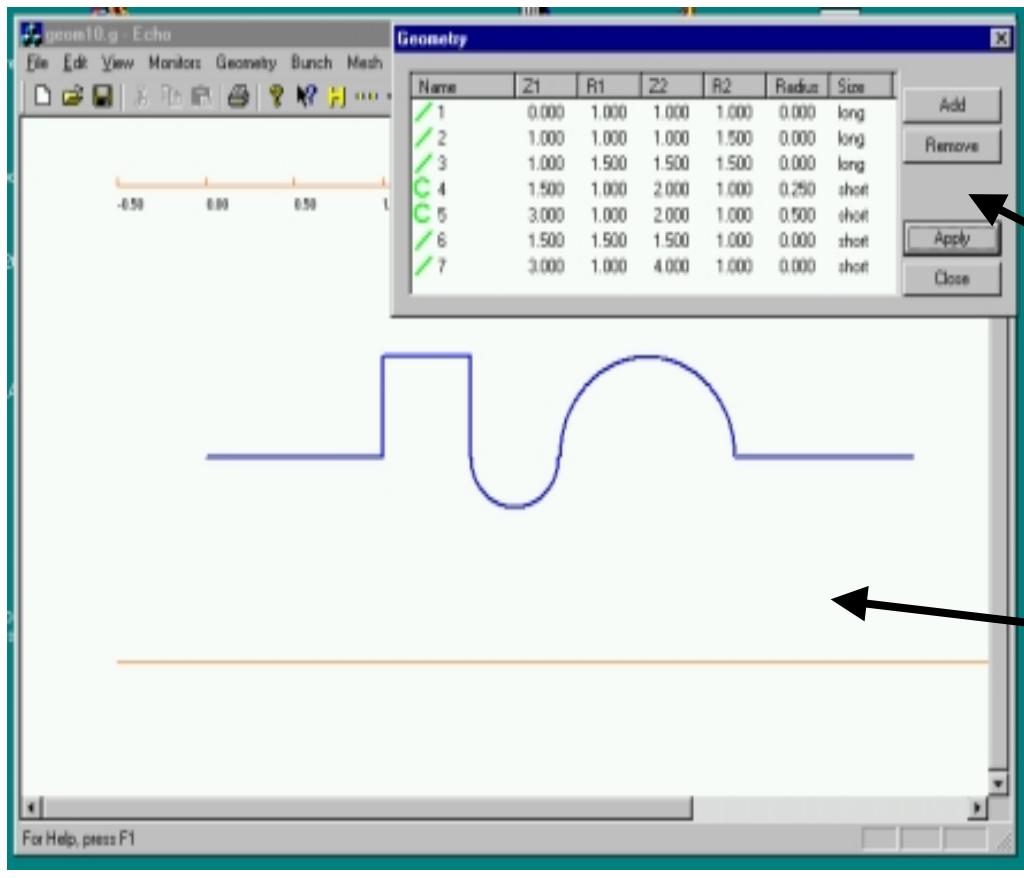


TTF RF-Gun Alignment: Before and After





A Code for Longitudinal Wake Field Calculation



The implicit scheme
[A.Novokhatski]:

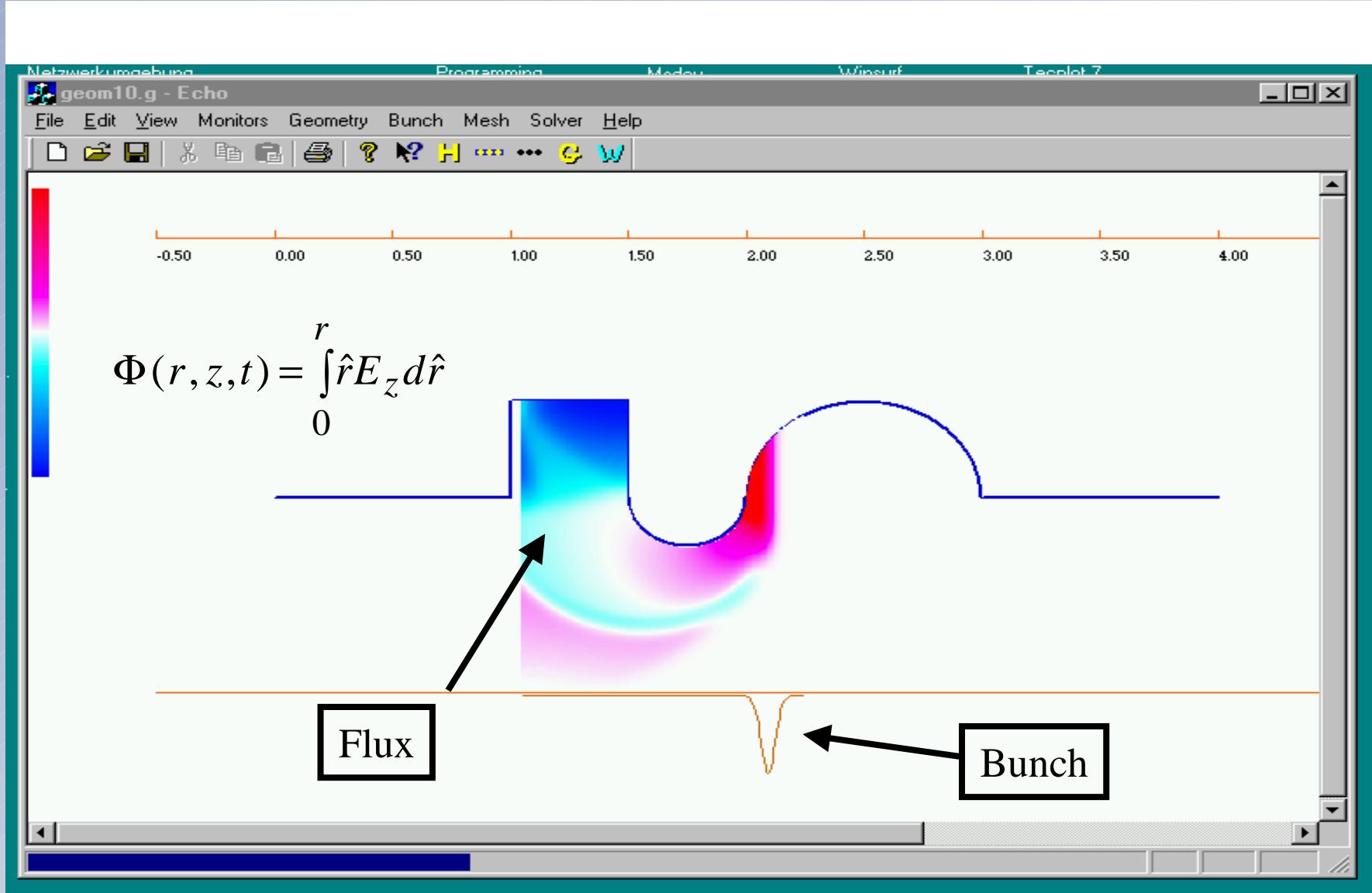
- does not have dispersion in longitudinal direction.
- allows calculation for very long structures
- travelling mesh

Geometry editor

Boundary shape

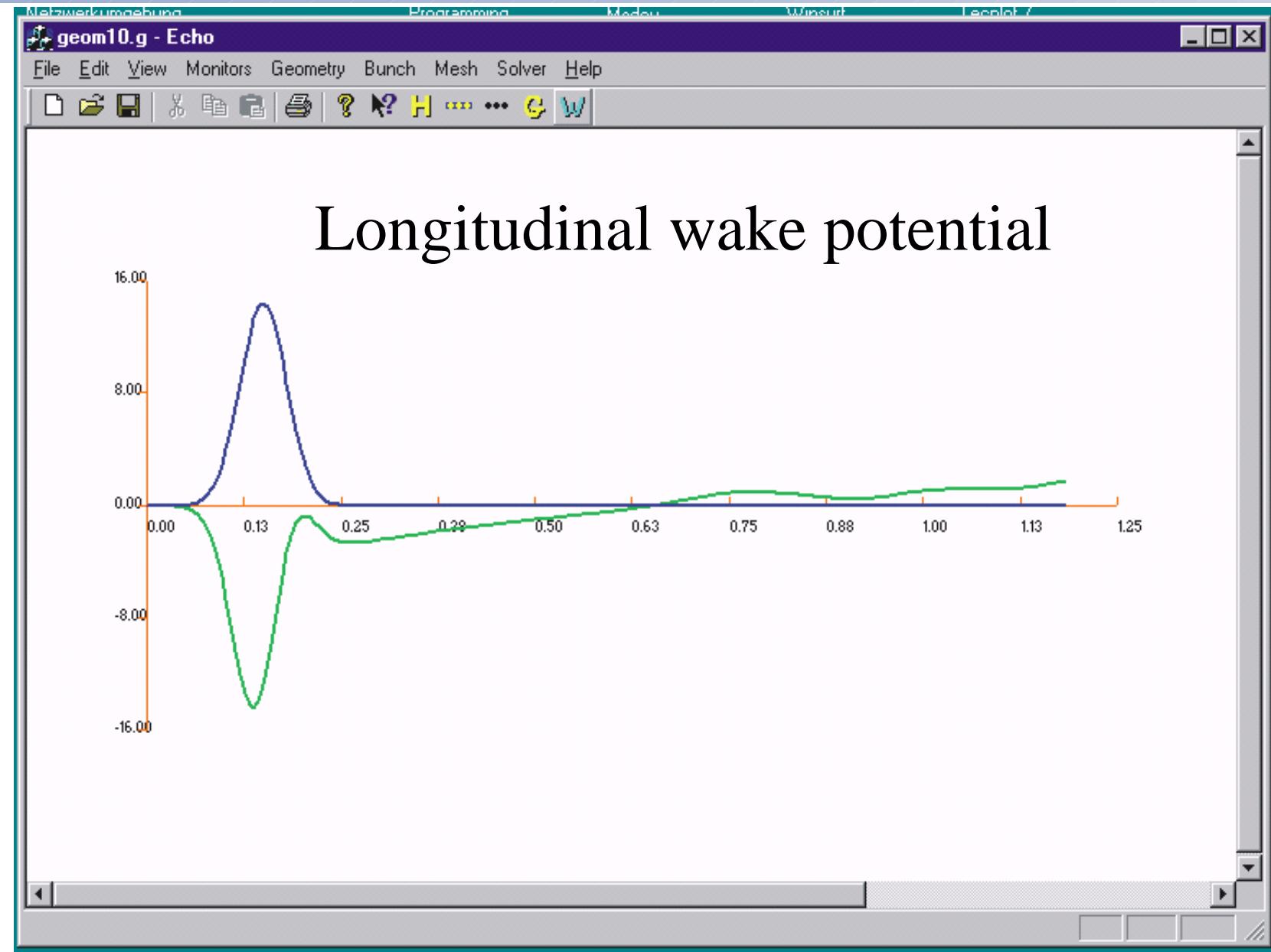


A Code for Longitudinal Wake Field Calculation





A Code for Longitudinal Wake Field Calculation



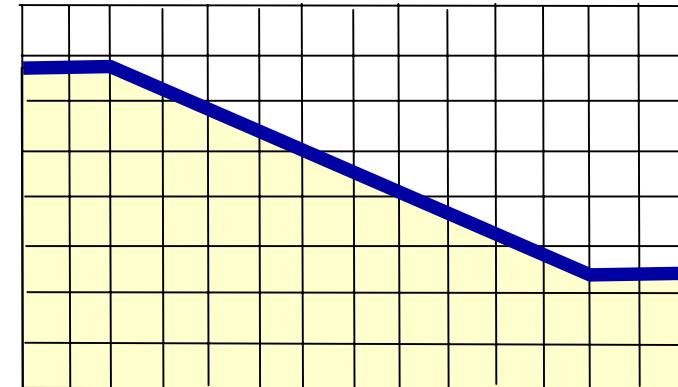


A Code for Longitudinal Wake Field Calculation

Staircase boundary approximation



Perfect boundary approximation



$O(h)$ —————→ $O(h^2)$

The new implicit scheme with perfect boundary approximation is developed.

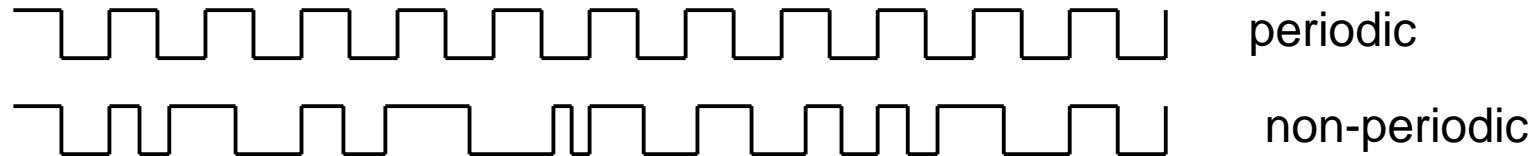
It will allow calculation of longitudinal wake potential for **long smooth structures**.



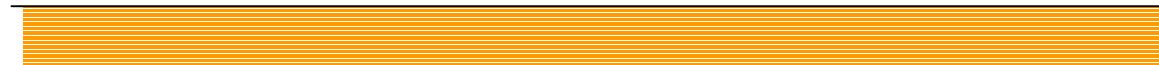
Investigation of Surface Roughness Wake Fields

- **Further studies on the rough tube model according to A.Novokhatski and M. Timm.**

- ◆ considered forms of 2D surface corrugations



- ◆ these corrugations are replaced by a single homogeneous layer of some equivalent dielectric constant

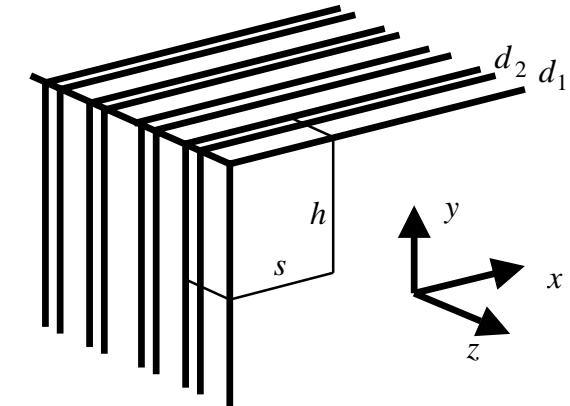


- ◆ So far always $\epsilon_r = 2$ was assumed, whilst the theoretical justification for this assumption was missing.

Wavenumber of Rough Tube Mode

- **anisotropic averaging** of the material distribution in the corrugation layer

$$\epsilon_z \approx \epsilon_1 \frac{d_1 + d_2}{d_1} \quad \epsilon_{x,y} \approx \frac{\kappa_2}{i\omega} \frac{d_2}{d_1 + d_2}$$



- new result for the wave number of the **rough tube mode** in contrast to the wave number of the thin dielectric layer mode

$$k_{0,RTM}^2 = \frac{2\epsilon_z}{R\delta} = \frac{2}{R\delta} \frac{d_1 + d_2}{d_1}$$

$$k_{0,TDL}^2 = \frac{2}{R\delta} \frac{\epsilon_r}{\epsilon_r - 1}$$

- this wavenumber is consistent with a mode matching calculation done by K. Bane and G. Stupakov
- further details see:
 - S.Ratschow, T. Weiland, M.Timm: On the mechanism of surface roughness wake field excitation. presented at PAC2001, Chicago, TOAA010.